

C0805H152F5GACTU

Aliases (C0805H152F5GAC7800) SMD Indust COG HT200C, Ceramic, 1,500 pF, 1%, 50 VDC, COG, SMD, MLCC, High Temperature, Ultra-Stable, Low Loss, 0805, 0.7 mm



| General Information | |
|--------------------------|--|
| Series | SMD Indust COG HT200C |
| Style | SMD Chip |
| Description | SMD, MLCC, High Temperature, Ultra-Stable, Low Loss |
| Features | High Temp, Ultra-Stable, Low Loss |
| RoHS | Yes |
| Termination | Tin |
| Marking | No |
| AEC-Q200 | No |
| Typical Component Weight | 13 mg |
| Shelf Life | 78 Weeks |
| MSL | 1 |

| Dimensions | |
|------------|-----------------|
| Chip Size | 0805 |
| L | 2mm +/-0.2mm |
| W | 1.25mm +/-0.2mm |
| Т | 0.9mm +/-0.10mm |
| S | 0.7mm MIN |
| В | 0.5mm +/-0.25mm |
| | |

| Specifications | |
|--|------------------------|
| Capacitance | 1,500 pF |
| Measurement Condition | 1 kHz 1.0Vrms |
| Tolerance | 1% |
| Voltage DC | 50 VDC |
| Dielectric Withstanding Voltage | 125 VDC |
| Temperature Range | -55/+200°C |
| Temp. Coefficient | COG |
| Capacitance Change with Reference to +25°C and 0 VDC Applied (TCC) | 30 ppm/C, 1kHz 1.0Vrms |
| Dissipation Factor | 0.1% 1 kHz 1.0Vrms |
| Aging Rate | 0% Loss/Decade Hour |
| Insulation Resistance | 100 GOhms |

| Packaging Specifications | |
|--------------------------|------------------------|
| Packaging | T&R, 180mm, Paper Tape |
| Packaging Quantity | 4000 |

| Statements of suitability for certain applications are based on our knowledge of typical operating conditions for such applications, but are not intended to constitute - and |
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